

🧲 Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Report No:CCIS15120098001

FCC REPORT

(Base Station)

Applicant: Baicells Technologies Co., Ltd.

Address of Applicant: 3F, Hui Yuan Development Building, No.1 Shangdi Information

Industry Base, Haidian Dist., Beijing, China

Equipment Under Test (EUT)

Product Name: LTE-TDD Base Station

Model No.: mBS1100

Trade mark: BaiCells

FCC ID: 2AG32MBS1100

IC ID: 20982-MBS1100

FCC CFR Title 47 Part 2

Applicable standards: FCC CFR Title 47 Part90 Subpart Z

RSS-Gen Issue 4, November 2014

RSS-197 Issue 1, February 2010

Date of sample receipt: 14 Dec., 2015

Date of Test: 15 Dec., 2015 to 25 Mar., 2016

Date of report issued: 29 Mar., 2016

Test Result: PASS*

* In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Bruce Zhang Laboratory Manager

This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product and does not permit the use of the CCISproduct certification mark. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.

This report may only be reproduced and distributed in full. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards.

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Report No: CCIS15120098001

2. Version

Version No.	Date	Description
00	29 Mar., 2016	Original

Tested by: Query Query Date: 29 Mar., 2016

Test Engineer

Reviewed by: Date: 29 Mar., 2016

Project Engineer





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4. Test Summary

Test Item	Section	Result	
rest item	FCC	IC	Result
RF Output Power	Part 2.1046	RSS Gen Section 6.12	Pass
1XI Output I owel	Part 90.1321	RSS 197 section 5.6	F 435
Modulation Characteristics	Part 2.1047	RSS 197 section 5.1	Pass
99% & -26 dB Occupied Bandwidth	Part 2.1049	RSS Gen section 6.6	Pass
99 % & -20 dB Occupied Baridwidth	Part 90.209	NOS Gen Section 6.0	F d 5 5
Emission Mask	Part 90.210(b)	Not applicable	Pass
Spurious Emissions at Antenna Terminal	Part 2.1051	RSS Gen Section 6.13	Pass
Spurious Emissions at Antenna Terminal	Part 90.1323	RSS 197 section 5.7	r ass
Field Strength of Spurious Radiation	Part 2.1053	RSS Gen Section 6.13	Pass
rield Strength of Spurious Madiation	Part 90.1323	RSS 197 section 5.7	r ass
Frequency stability vs. temperature	Part 2.1055(a)(1)(b)	RSS Gen section 6.11	Pass
r requericy stability vs. temperature	Part 90.213(a)	RSS 197 section 5.3	1 035
Frequency stability vs. voltage	Part 2.1055(d)(1)(2)	RSS Gen section 6.11	Pass
Trequency stability vs. voltage	Part 90.213(a)	RSS 197 section 5.3	1 033

Pass: The EUT complies with the essential requirements in the standard.



5. General Information

5.1 Client Information

Applicant:	Baicells Technologies Co., Ltd.
Address of Applicant:	3F, Hui Yuan Development Building, No.1 Shangdi Information Industry Base, Haidian Dist., Beijing, China
Manufacturer	Baicells Technologies Co., Ltd.
Address of Manufacturer:	3F, Hui Yuan Development Building, No.1 Shangdi Information Industry Base, Haidian Dist., Beijing, China

5.2 General Description of E.U.T.

Product Name:	LTE-TDD Base Station
Model No.:	mBS1100
Operation Frequency range:	3655MHz~3695MHz
Modulation type:	BPSK,QPSK,16QAM,64QAM
Antenna type:	External antenna ("N" type)
Antenna gain:	7 dBi
Power supply:	DC 48V

Test Channle:

101	ЛНz	20MHz		
Channel: Frequency (MHz)		Channel:	Frequency (MHz)	
Lowest	3655	Lowest	3660	
Middle	3675	Middle	3675	
Highest	3695	Highest	3690	

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5.3 Test modes

Data mode (QPSK)	Keep the EUT in data communicating mode (QPSK). (10MHz, 20MHz)
Data mode (64QAM)	Keep the EUT in data communicating mode (64QAM). (10MHz, 20MHz)

5.4 Description of Support Units

Manufacturer Description		Model	Serial Number	FCC ID/DoC	
INVENTR@NICS°	LED DRIVER	EUV-200S048SV	N/A	N/A	

5.5 Related Submittal(s) / Grant (s)

FCC: This submittal(s) (test report) is filing to comply with Section Part 90 subpart Z of the FCC CFR 47 Rules.

IC: This submittal(s) (test report) is filing to comply with RSS 197

5.6 Test Methodology

FCC: Both conducted and radiated testing were performed according to the procedures document on TIA/EIA 603 and FCC CFR 47.1046, 2.1047, 2.1049, 2.1051, 2.1053, 2.1055 and 2.1057 IC: Both conducted and radiated testing were performed according to RSS Gen, RSS 197, ANSI C63.10:2009.

5.7 Laboratory Facility

The test facility is recognized, certified, or accredited by the following organizations:

• FCC - Registration No.: 817957

Shenzhen Zhongjian Nanfang Testing Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in out files. Registration 817957, February 27, 2012.

• IC - Registration No.: 10106A-1

The 3m Semi-anechoic chamber of Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been Registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 10106A-1.

• CNAS - Registration No.: CNAS L6048

Shenzhen Zhongjian Nanfang Testing Co., Ltd. is accredited to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration laboratories for the competence of testing. The Registration No. is CNAS L6048.

5.8 Laboratory Location

Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Address: No.B-C, 1/F., Building 2, Laodong No.2 Industrial Park, Xixiang Road,

Bao'an District, Shenzhen, Guangdong, China

Tel: +86-755-23118282 Fax: +86-755-23116366

Shenzhen Zhongjian Nanfang Testing Co., Ltd. No.B-C, 1/F., Building 2, Laodong No.2 Industrial Park, Xixiang Road, Bao'an District, Shenzhen, Guangdong, China Telephone: +86 (0) 755 23118282 Fax: +86 (0) 755 23116366 Project No.: CCIS151200980RF

Report No: CCIS15120098001





5.9 Test Instruments list

10011110114					
Test Equipment	Manufacturer Model No.		Inventory No.	Cal. Date (mm-dd-yy)	Cal. Due date (mm-dd-yy)
3m SAC	SAEMC	9(L)*6(W)* 6(H)	CCIS0001	08-23-2014	08-22-2017
BiConiLog Antenna	SCHWARZBECK	VULB9163	CCIS0005	03-28-2015	03-28-2016
Horn Antenna	SCHWARZBECK	BBHA9120D	CCIS0006	03-28-2015	03-28-2016
Pre-amplifier (10kHz-1.3GHz)	HP	8447D	CCIS0003	04-01-2015	03-31-2016
Pre-amplifier (1GHz-18GHz)	Compliance Direction Systems Inc.	PAP-1G18	CCIS0011	04-01-2015	03-31-2016
Pre-amplifier (18-26GHz)	Rohde & Schwarz	AFS33-18002 650-30-8P-44	GTS218	04-01-2015	03-31-2016
Horn Antenna	ETS-LINDGREN	3160	GTS217	04-01-2015	03-31-2016
Spectrum analyzer 9k-30GHz	Rohde & Schwarz	FSP30	CCIS0023	03-28-2015	03-28-2016
Spectrum Analyzer 20Hz-26.5GHz	Agilent	N9020A	MY50510123	10-29-2015	10-29- 2016
EMI Test Receiver	Rohde & Schwarz	ESRP7	CCIS0167	03-28-2015	03-28-2016
Loop antenna	Laplace instrument	RF300	EMC0701	04-01-2015	03-31-2016



6. System test configuration

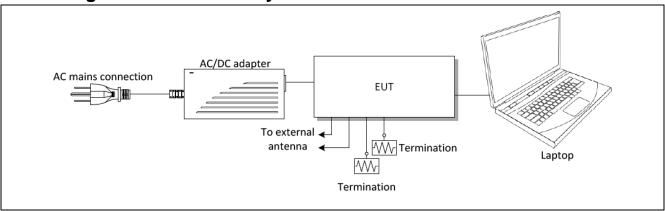
6.1 EUT Configuration

The EUT configuration for testing is installed on RF field strength measurement to meet the commission's requirement and operating in a manner which intends to maximize its emission characteristics in a continuous normal application.

6.2 EUT Exercise

The EUT (Transmitter) was operated in the engineering mode to fix the Tx frequency which was for the purpose of the measurements.

6.3 Configuration of Tested System



6.4 Description of Test Modes

The EUT has been tested under operating condition.

EUT staying in continuous transmitting mode. Channel Low, Mid and High for each type band with rated data rate were chosen for full testing.

The field strength of spurious radiation emission was measured as EUT stand-up position (H mode) and lie down position (E1, E2 mode) for three modes with power adaptor, earphone and Data cable. The worst-case H mode.

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6.5 Transmit Output Power and PSD

Test Requirement:	FCC part90.1321(a) and RSS-197 Clause 5.6.2
Test Method:	FCC part2.1046 and RSS Gen section 6.12
Limit:	FCC: (a) Base and fixed stations are limited to 25 watts/25 MHz equivalent isotropically radiated power (EIRP). In any event, the peak EIRP powerdensity shall not exceed 1 Watt in any one-megahertz slice of spectrum. (b) In addition to the provisions in paragraph (a) of this section, transmitters operating in the 3650-3700 MHz band that emit multipledirectional beams, simultaneously or sequentially, for the purpose of directing signals to individual receivers or to groups of receivers provided theemissions comply with the following: (1) Different information must be transmitted to each receiver. (2) If the transmitter employs an antenna system that emits multiple directional beams but does not emit multiple directional beamssimultaneously, the total output power conducted to the array or arrays that comprise the device, i.e., the sum of the power supplied to allantennas, antenna elements, staves, etc. and summed across all carriers or frequency channels, shall not exceed the limit specified in paragraph(a) of this section, as applicable. The directional antenna gain shall be computed as follows: (i) The directional gain, in dBi, shall be calculated as the sum of 10 log (number of array elements or staves) plus the directional gain, in dBi, of the individual element or stave having the highest gain. (ii) A lower value for the directional gain than that calculated in paragraph (b)(2)(i) of this section will be accepted if sufficient evidence ispresented, e.g., due to shading of the array or coherence loss in the beam-forming. (3) If a transmitter employs an antenna that operates simultaneously on multiple directional beams using the same or different frequencychannels and if transmitted beams overlap, the power shall be reduced to ensure that the aggregate power from the overlapping beams does notexceed the limit specified in paragraph (b)(2) of this section. In addition, the aggregate power transmitted simultaneously on all beams shall notexceed the limit specified in paragraph (b)(2) of this section. In
Test Procedure:	RBW=1MHz, VBW=3MHz, Detector mode= RMS , Trace mode: Power averaging over 100 sweeps
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed

Measurement Data

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	Transmit Output Power								
Bandwidth (MHz)	Modulation	Test Channel	Chain 0 Output Power (dBm/10MHz)	Chain 1 Output Power (dBm/10MHz)	Total Power (dBm/10MHz)	Antenna Gain (dBi)	EIRP (dBm/10MHz)	EIRP Limit (dBm/10MHz)	
		Lowest	25.69	25.66	28.69	10	38.69		
	QPSK	Middle	25.54	25.57	28.57	10	38.57		
10		Highest	25.58	25.55	28.58	10	38.58	40.00	
10	64QAM	Lowest	25.75	25.74	28.76	10	38.76	40.00	
		Middle	25.60	25.61	28.62	10	38.62		
		Highest	25.53	25.49	28.52	10	38.52		
Bandwidth (MHz)	Modulation	Test Channel	Chain 0 Output Power (dBm/20MHz)	Chain 1 Output Power (dBm/20MHz)	Total Power (dBm/20MHz)	Antenna Gain (dBi)	EIRP (dBm/20MHz)	EIRP Limit (dBm/20MHz)	
		Lowest	28.55	28.53	31.55	10	41.55		
	QPSK	Middle	28.44	28.46	31.46	10	41.46		
20		Highest	28.58	28.55	31.58	10	41.58	43.01	
20	64QAM	Lowest	28.72	28.77	31.76	10	41.76	43.01	
		Middle	28.66	28.69	31.69	10	41.69		
		Highest	28.61	28.65	31.64	10	41.64		

	PSD							
Bandwidth (MHz)	Modulation	Test Channel	Chain 0 PSD (dBm/MHz)	Chain 1 PSD (dBm/MHz)	Total PSD (dBm/MHz)	Antenna Gain (dBi)	EIRP density (dBm/MHz)	EIRP density Limit (dBm/MHz)
		Lowest	16.68	16.75	19.73	10	29.73	
	QPSK	Middle	16.76	16.66	19.72	10	29.72	
10		Highest	16.60	16.71	19.67	10	29.67	30.00
10	64QAM	Lowest	16.60	16.44	19.53	10	29.53	30.00
		Middle	16.49	16.64	19.58	10	29.58	
		Highest	16.42	16.53	19.49	10	29.49	
Bandwidth (MHz)	Modulation	Test Channel	Chain 0 PSD (dBm/MHz)	Chain 1 PSD (dBm/MHz)	Total PSD (dBm/MHz)	Antenna Gain (dBi)	EIRP density (dBm/MHz)	EIRP density Limit (dBm/MHz)
		Lowest	14.98	15.26	18.13	10	28.13	
	QPSK	Middle	14.94	15.16	18.06	10	28.06	
20		Highest	15.12	15.13	18.14	10	28.14	30.00
20		Lowest	15.16	15.17	18.18	10	28.18	30.00
	64QAM	Middle	15.28	15.10	18.20	10	28.20	
		Highest	15.06	15.02	18.05	10	28.05	

Remark: Directional antenna Gain = Antenna Gain + 10 \lg (ANT_N) = 10 \lg



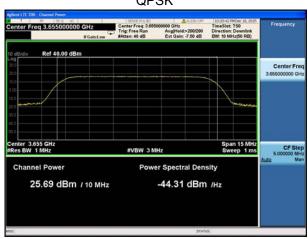
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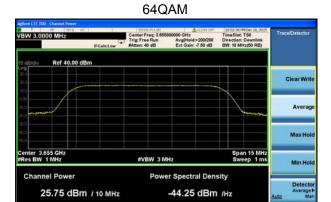
Power

Chain 0:

10MHz

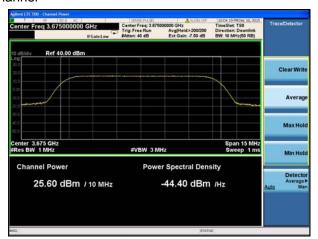
QPSK

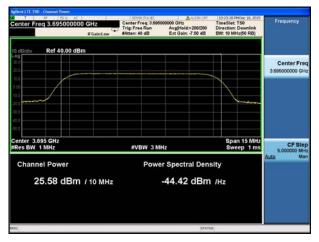




Lowest channel









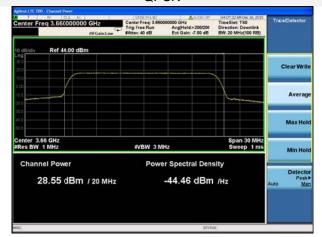
Highest channel



20MHz

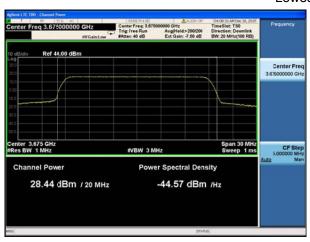
QPSK

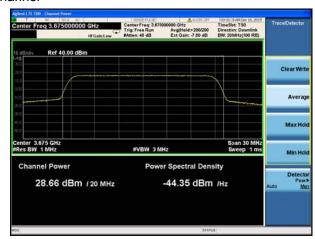
64QAM

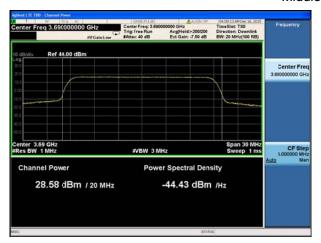


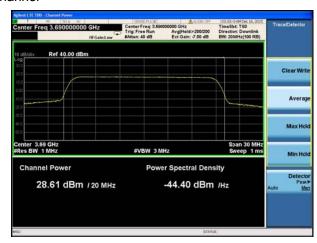


Lowest channel









Highest channel



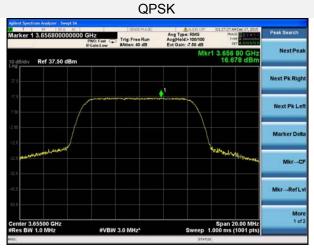


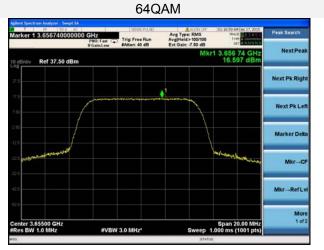
PSD

Chain 0:

10MHz

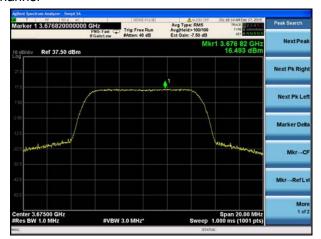
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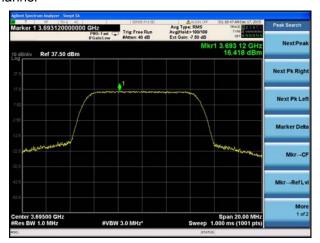


Lowest channel







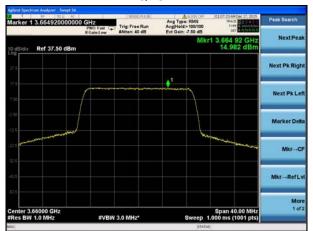


Highest channel



20MHz

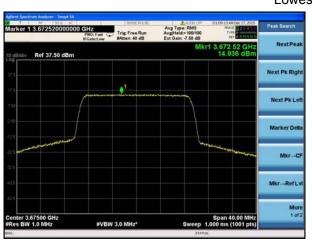
QPSK



64QAM



Lowest channel









Highest channel

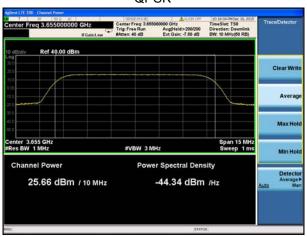


Power

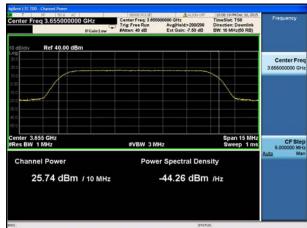
Chain 1:

10MHz

QPSK

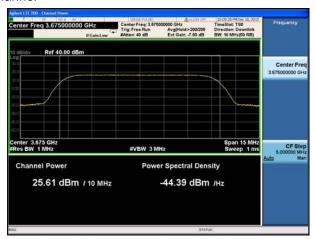


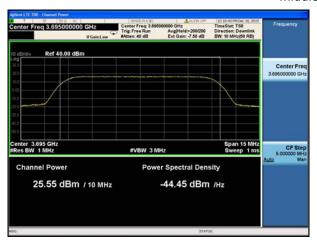
64QAM



Lowest channel







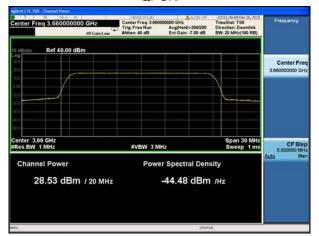


Highest channel

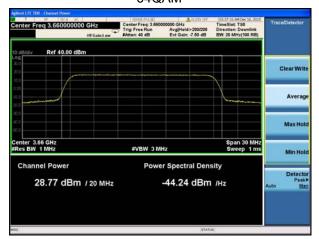


20MHz

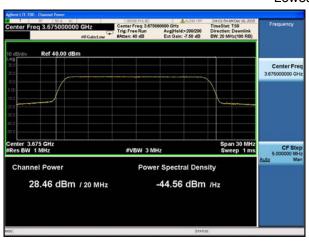
QPSK

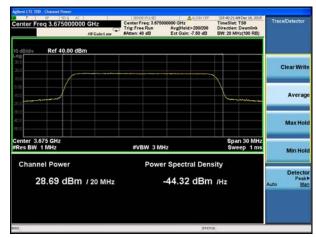


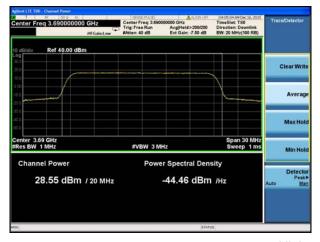
64QAM

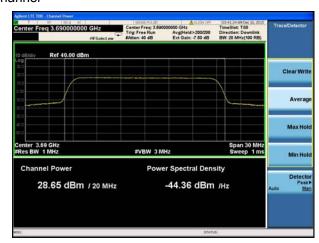


Lowest channel









Highest channel





PSD

Chain 1:

10MHz

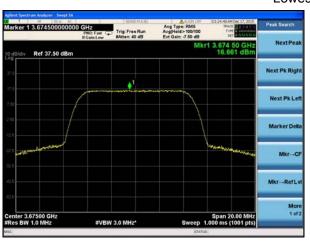
QPSK



64QAM

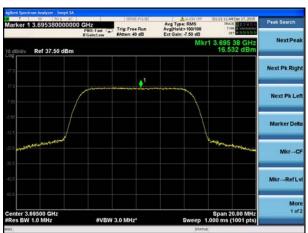


Lowest channel









Highest channel

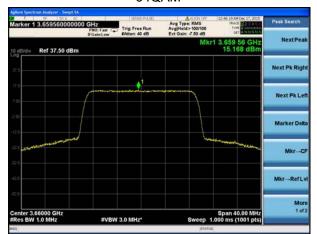


20MHz

QPSK

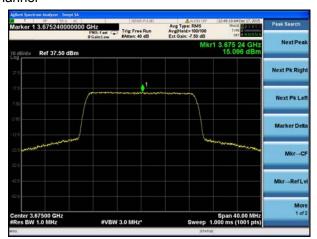


64QAM

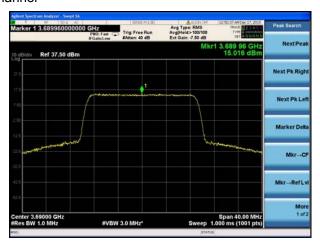


Lowest channel









Highest channel



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6.6 Occupy Bandwidth

Test Requirement:	FCC part 90.209 andRSS-Gen 6.6		
Test Method:	FCC part 2.1049 and RSS-Gen 6.6		
Test Procedure:	The EUT's output RF connector was connected with a short cable to the spectrum analyzer		
	The transmitter shall be operated at its maximum carrier powermeasured under normal test conditions.		
	 The span of the analyzer shall be set to capture all products of themodulation process, including the emission skirts. 		
	4. The resolution bandwidth (RBW) shall be in the range of 1% to 5% ofthe occupied bandwidth (OBW) and video bandwidth (VBW) shall beapproximately 3x RBW.		
Test Instruments:	Refer to section 5.8 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		

Measurement Data





Chain 0:

Bandwidth(MHz)	Modulation	Test Channel	99% Occupy bandwidth (MHz)
		Lowest	9.043
	QPSK	Middle	9.049
10		Highest	9.045
10		Lowest	9.048
	64QAM	Middle	9.050
		Highest	9.048
	QPSK	Lowest	17.885
		Middle	17.877
20		Highest	17.883
20	64QAM	Lowest	17.881
		Middle	17.870
		Highest	17.871

Chain 1:

Bandwidth(MHz)	Modulation	Test Channel	99% Occupy bandwidth (MHz)
		Lowest	9.043
	QPSK	Middle	9.045
10		Highest	9.055
10		Lowest	9.042
	64QAM	Middle	9.046
		Highest	9.051
	QPSK 64QAM	Lowest	17.870
		Middle	17.871
20		Highest	17.880
20		Lowest	17.883
		Middle	17.876
		Highest	17.870

Test plot as follows:





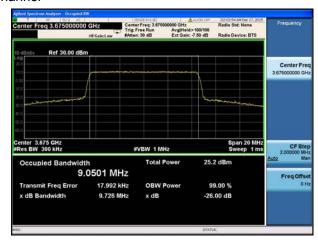
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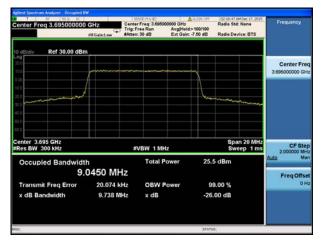
10MHz

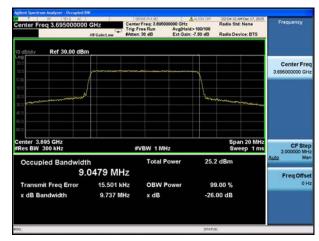


Lowest channel







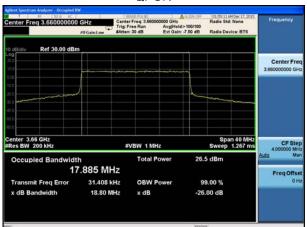


Highest channel

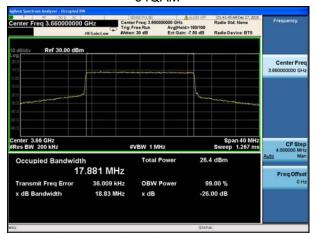


20MHz

QPSK

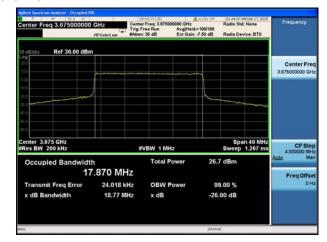


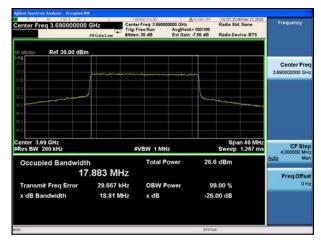
64QAM



Lowest channel







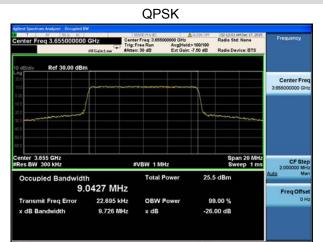


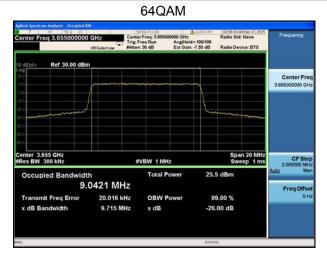
Highest channel



Chain 1:

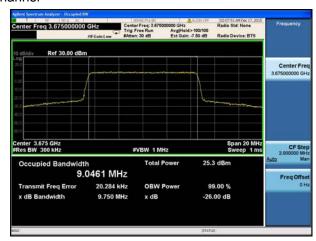
10MHz



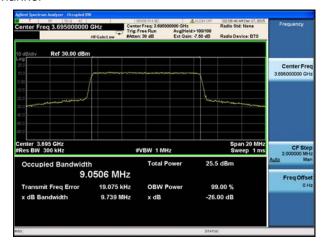


Lowest channel







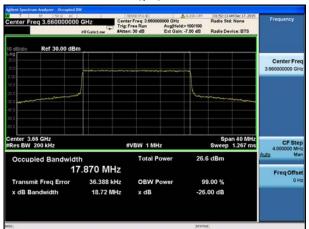


Highest channel

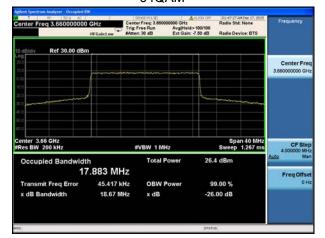


20MHz

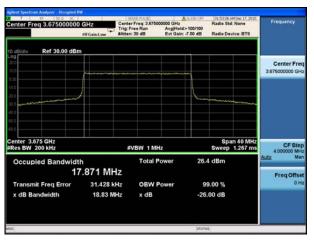
QPSK

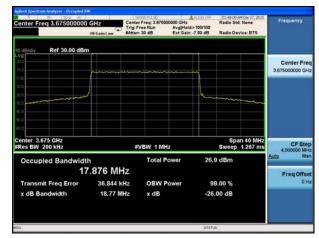


64QAM



Lowest channel









Highest channel





6.7 Emission Mask

Test Requirement:	FCC part 90.210(b)	
Limit:	Emission Mask B. For transmitters that are equipped with an audio low-pass filter, the power of any emission must be attenuated belowthe unmodulated carrier power (P) as follows: (1) On any frequency removed from the assigned frequency by more than 50 percent, but not more than 100 percent of the authorizedbandwidth: At least 25 dB. (2) On any frequency removed from the assigned frequency by more than 100 percent, but not more than 250 percent of the authorizedbandwidth: At least 35 dB. (3) On any frequency removed from the assigned frequency by more than 250 percent of the authorized bandwidth: At least 43 + 10 log (P)dB.	
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. RBW=100kHz, VBW=1MHz, Detector mode= RMS, Trace mode: Power averaging over 100 sweeps 	
Test Instruments:	Refer to section 5.8 for details	
Test mode:	Refer to section 5.3 for details	
Test results:	Passed	

Measurement Data:

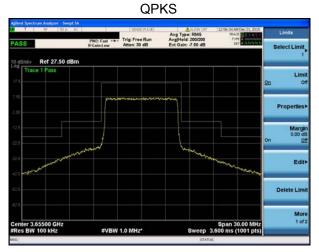


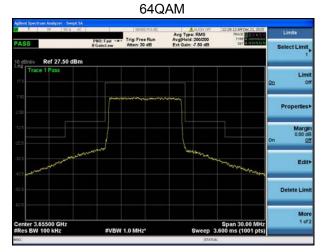


Test plots as below:

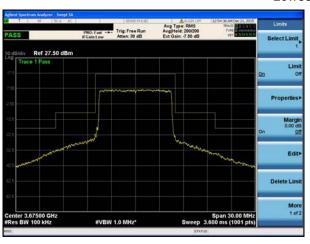
Chain 0:

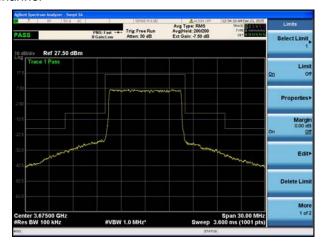
10MHz

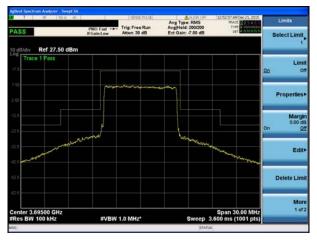


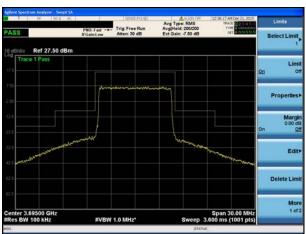


Lowest channel







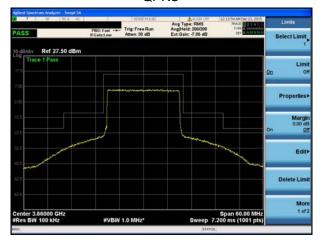


Highest channel

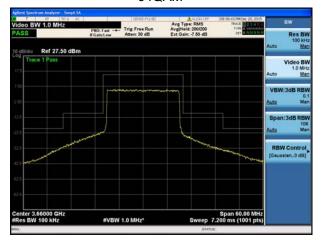


20MHz

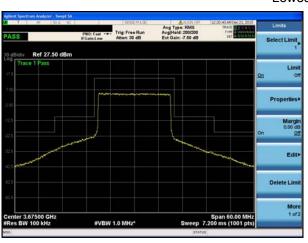
QPKS

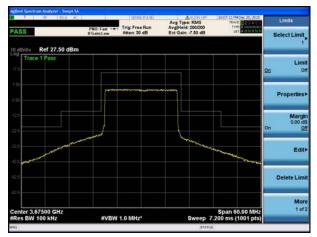


64QAM

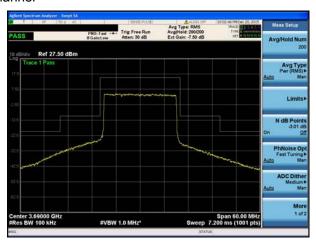


Lowest channel









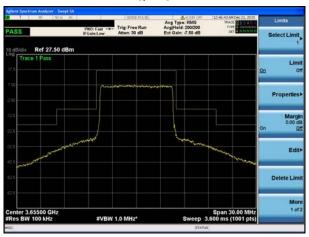
Highest channel



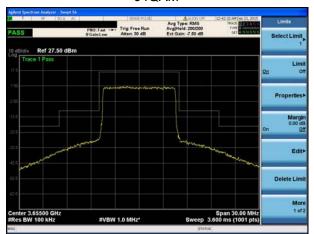
Chain 1:

10MHz

QPKS

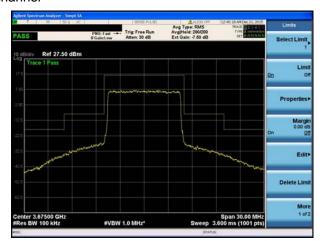


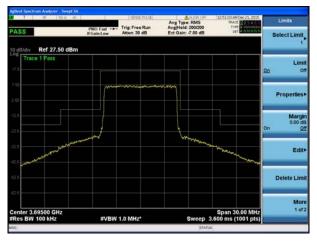
64QAM

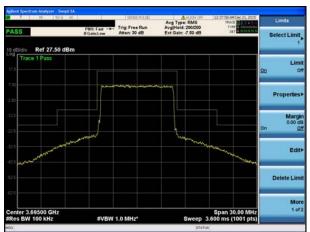


Lowest channel







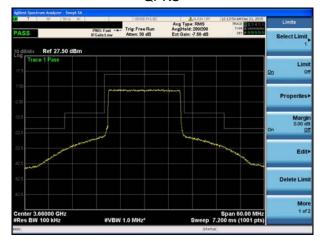


Highest channel

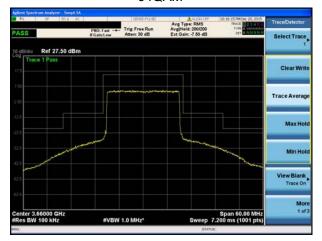


20MHz

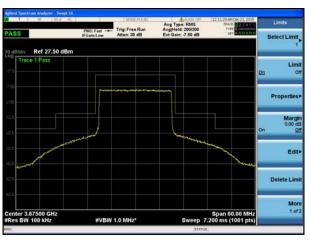
QPKS

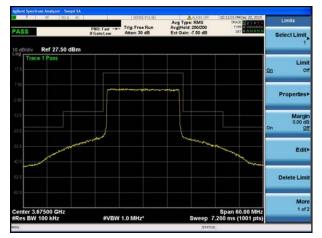


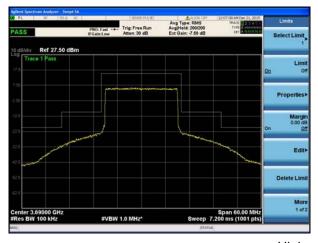
64QAM



Lowest channel









Highest channel



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6.8 Out of band emission at antenna terminals

Test Requirement:	FCC part90.1323 and RSS-197 Clause 5.7		
Test Method:	FCC part2.1051 and RSS Gen Section 6.13		
Limit:	-13dBm		
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 100 kHz when below 1GHz, 1MHz when above 1 GHz; sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=100 kHz, VBW=300 kHz when below 1 GHz, RBW =1 MHz, VBW=3 MHz when above 1 GHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions. 		
Test Instruments:	Refer to section 5.8 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		
Remark:	During the test, pre-scan the QPSK, 64QAM modulation, and found the QPSK modulation(10MHz/20MHz middle channel) is the worst case.		

Test plots as follows(worst case):

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Spurious emission

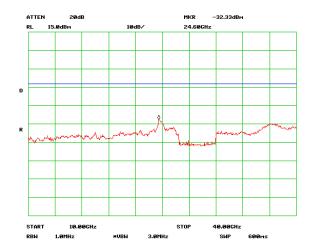
Chain 0:



30MHz~1GHz

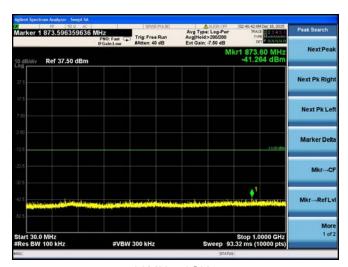


1GHz~10GHz



10GHz~40GHz

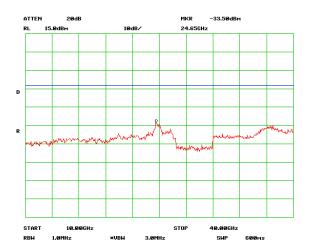




30MHz~1GHz



1GHz~10GHz

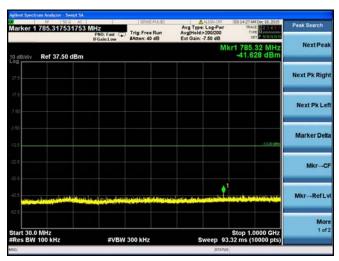


10GHz~40GHz





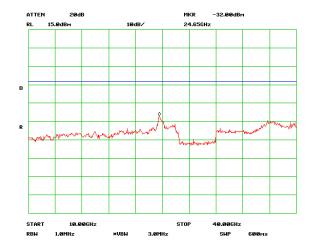
Chain 1:



30MHz~1GHz



1GHz~10GHz



10GHz~40GHz

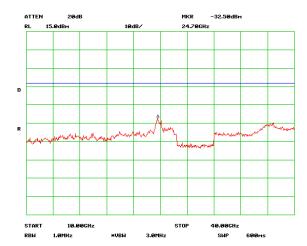




30MHz~1GHz



1GHz~10GHz



10GHz~40GHz



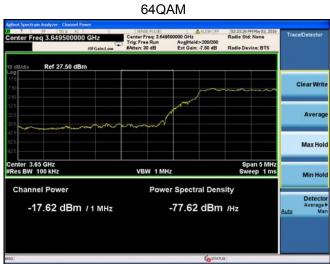


Band edge emission:

Chain 0:

10MHz





Lowest channel

Lowest channel





Highest channel

Highest channel





20MHz

Agliert Sjectram Analyzer - Obered Pieers Str. Center Freq 3.649500000 GHz Frequency | Center Freq 3.649500000 GHz | Center Freq 3.649500000 GHz | Frequency | Center Freq 3.649500000 GHz | Frequency | Frequency | Radio Std: None | Radio Device: BTS | 10 dBlodiv | Ref 27.50 dBm | Radio Device: BTS | Radio Device: BTS | 10 dBlodiv | Ref 27.50 dBm | Radio Device: BTS | Radio Device: BTS | 10 dBlodiv | Ref 27.50 dBm | Radio Device: BTS | Radio Device: BTS | Radio Device: BTS | 10 dBlodiv | Ref 27.50 dBm | Radio Device: BTS | Radio Device:



Lowest channel

Lowest channel





Highest channel

Highest channel

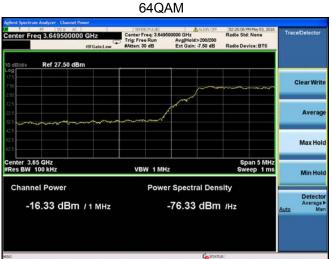




Chain 1:

10MHz

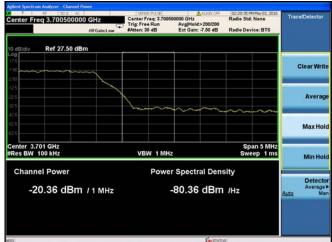




Lowest channel

Lowest channel



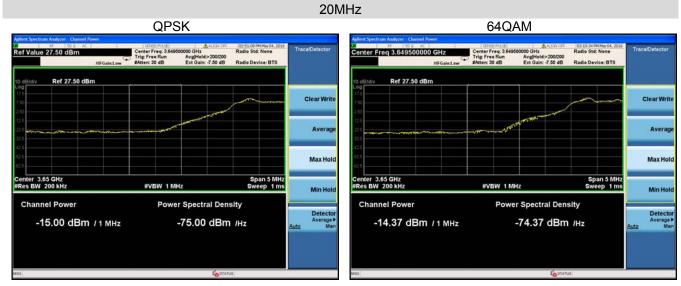


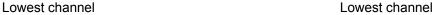
Highest channel

Highest channel











Highest channel Highest channel





6.9 Field strength of spurious radiation measurement

Test Requirement:	FCC part22.917(a), FCC part24.238(a)
Test Method:	FCC part2.1053
Limit:	-13dBm
Test setup:	Below 1GHz
	Antenna Tower Search Antenna RF Test Receiver Tum Table Ground Plane
	Above 1GHz
	Antenna Tower Horn Antenna Spectrum Analyzer Turn Table A A A A A A A A A A A A A A A A A A A
	Substituted method:
	Ground plane d: distance in meters d:3 meter 1-4 meter S.G. Substituted Dipole or Horn Antenna Bi-Log Antenna or Horn Antenna
Test Procedure:	The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. During the tests, the entenne height and the ELIT arimuth were
	During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations. The frequency range up to test bearing was investigated for each account.
	 The frequency range up to tenth harmonic was investigated for each of three fundamental frequency (low, middle and high channels). Once spurious emission was identified, the power of the emission was determined using the substitution method.





	The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) – Cable Loss (dB)
Test Uncertainty:	± 4.88 dB
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details.
Test results:	Passed
Remark:	During the test, pre-scan the QPSK, 64QAM modulation, and found the QPSK modulation is the worst case.

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Measurement Data (worst case):

wicasurement Data (v	Measurement Data (worst case):						
10MHz for QPSK							
Frequency (MHz)	Polarization	Emission Level (dBm)	Limit (dBm)	Result			
Lowest							
5164.10	Vertical	-36.98					
5478.26	Vertical	-38.19					
7310.00	V	-42.92					
	V		_				
10965.00		-38.46	-13	Pass			
5300.20	Horizontal	-42.35					
5487.26	H	-34.53					
7310.00	Н	-42.52					
10965.00	Н	-38.40					
	Middle						
5330.93	Vertical	-42.36		Pass			
5519.07	V	-40.36					
7350.00	V	-43.02	-13				
11025.00	V	-39.64					
5300.20	Horizontal	-42.89	-13				
5519.07	I	-34.22					
7350.00	Н	-42.77					
11025.00	Н	-39.69					
		Highest					
5179.05	Vertical	-41.29					
5535.05	V	-39.70	1				
7390.00	V	-42.21	1				
11085.00	V	-39.48	-13				
5269.65	Horizontal	-39.25		Pass			
5551.07	Н	-35.33	1				
7390.00	Н	-40.49	1				
11085.00	Н	-39.28	1				
			1	l			

Remark:

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.





20MHz for QPSK							
(\A)	Spurious	Emission	Lineit (dDas)	Desult			
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result			
	Lowest						
5300.02	Vertical	-40.84					
5487.26	V	-37.88					
7320.00	V	-42.49					
10980.00	V	-38.68	40	Dese			
5487.26	Horizontal	-34.55	-13	Pass			
5915.52	Н	-39.33					
7320.00	Н	-42.73					
10980.00	Н	-39.00					
	Middle						
5179.05	Vertical	-37.91		Pass			
5503.14	V	-41.49	-				
7350.00	V	-41.94					
11025.00	V	-39.14					
5179.05	Horizontal	-35.89	13				
5519.07	Н	-32.42					
7350.00	Н	-41.70					
11025.00	Н	-40.14					
		Highest					
5179.05	Vertical	-42.96					
5330.93	V	-41.63		Pass			
7380.00	V	-41.28					
11070.00	V	-38.53	-13				
5194.04	Horizontal	-40.48		F 455			
5535.05	Н	-36.15					
7380.00	Н	-40.87					
11070.00	Н	-39.23					

Remark:

1. The emission levels of below 1 GHz are very lower than the limit and not show in test report.

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6.10 Frequency stability V.S. Temperature measurement

Test Requirement:	FCC Part90.213(a) and RSS 197 section 5.3			
Test Method:	FCC Part2.1055(a)(1)(b) and RSS Gen section 6.1.1			
	FCC:			
	Frequency range (MHz)	Fixed and base stations (±ppm)	Mobile station Over 2 watts output power	ons (±ppm) 2 watts or less output power
	Below 25	100	100	200
	25–50 72–76	20 5	20	50 50
	150-174	5	5	50
	216-220 220-222	1.0 0.1	1.5	1.0 1.5
	421-512 806-809	2.5 1.0	5 1.5	5 1.5
	809-824	1.5	2.5	2.5
	851-854 854-869	1.0 1.5	1.5 2.5	1.5 2.5
	896-901 902-928	0.1 2.5	1.5 2.5	1.5 2.5
	902-928	2.5	2.5	2.5
Limit:	929–930 935–940	1.5 0.1	1.5	1.5
LIIIII.	1427–1435 Above 2450	300	300	300
	(a) The frequency offse Gen and recorded; (b) Using a resolution be unwanted emission highest channel sha as fL and fH respec	ncy stability limit shall be et shall be measured accor- pandwidth of 1% of the oc- level specified in Section all be selected, and the fractively.	ording to the procedure ccupied bandwidth, a re n 5.7 on the emission mequency at these point	e described in RSS- eference point at the nask of the lowest and s shall be recorded
	1.1	ncy offset shall be within	=	
Test setup:			Temperature Chamber	
	Note: M	Spectrum analyzer Att. Att.	Variable Power S	j jupply
Test procedure:		nt under test was c	connected to an ex	xternal DC power
	RF output wanalyzer via fe	put rated voltage. vas connected to a eed through attenua	itors.	
		placed inside the te	•	
		trum analyzer RBW colution and measur quency.		
	5. Turn EUT off temperature frequency.	and set the chamb stabilized for appro	oximately 30 minu	tes recorded the
		of +50℃ reached	norcascu per sidy	e unui uie iligilest
Test Instruments:	Refer to section 5.	Refer to section 5.8 for details		
Test mode:	Refer to section 5.	Refer to section 5.3 for details		
Test results:	Passed			
Remark:		of all modulations horst modulation sho		-





Measurement Data (the worst channel):

Chain 0.

	Frequency: Lowest channel=3		
Power supplied (Vdc)	Temperature (°C)	Frequency error	
1 ower supplied (vdo)	remperature (©)	Hz	ppm
	-35	162	0.044323
	-20	124	0.033926
	-10	105	0.028728
	0	123	0.033653
48.00	10	130	0.035568
	20	133	0.036389
	30	107	0.029275
	40	145	0.039672
	55	139	0.038030
Reference	Frequency: Lowest channel=3	660MHz(20MHz for C	PSK)
Dower ownlied ()/de)	To non orations (°C)	Freq	uency error
Power supplied (Vdc)	Temperature (℃)	Hz	ppm
	-35	154	0.042134
	-20	126	0.034473
	-10	104	0.028454
	0	135	0.036936
48.00	10	147	0.040219
	20	108	0.029549
- -	30	126	0.034473
	40	128	0.035021
	55	150	0.041040





Chain 1:

Chain 1:					
Reference Frequency: Lowest channel=3655MHz(10MHz for QPSK)					
Power supplied (Vdc)	Temperature (℃)	Fre	quency error		
1 ower supplied (vde)	remperature (©)	Hz	ppm		
	-35	159	0.043502		
	-20	127	0.034747		
	-10	110	0.030096		
	0	126	0.034473		
48.00	10	129	0.035294		
	20	130	0.035568		
	30	111	0.030369		
	40	147	0.040219		
	55	140	0.038304		
Reference	Frequency: Lowest channel=	3660MHz(20MHz for	QPSK)		
Davier avention (Ada)	Temperature (℃)	Frequency error			
Power supplied (Vdc)		Hz	ppm		
	-35	150	0.041040		
	-20	122	0.033379		
	-10	111	0.030369		
	0	139	0.038030		
48.00	10	144	0.039398		
	20	112	0.030643		
	30	123	0.033652		
	40	124	0.033926		
	55	153	0.041860		



6.11 Frequency stability V.S. Voltage measurement

Test Requirement:	FCC Part 90.213(a) a	FCC Part 90.213(a) and RSS 197 section 5.3				
Test Method:		FCC Part 2.1055(a)(1)(b) and RSS Gen section 6.1.1				
	FCC:					
	Frequency range (MHz)	ixed and base stations (±ppm)	Mobile station Over 2 watts output power	ns (±ppm) 2 watts or less output power		
	Below 25	100	100	200		
	25–50 72–76	20 5	20	50 50		
	150-174	5	5	50		
	216-220 220-222	1.0 0.1	1.5	1.0 1.5		
	421-512	2.5	5	5		
	806-809	1.0	1.5	1.5		
	809-824 851-854	1.5 1.0	2.5 1.5	2.5 1.5		
	854-869	1.5	2.5	2.5		
	896-901 903-938	0.1 2.5	1.5 2.5	1.5 2.5		
	902–928 902–928	2.5	2.5	2.5		
Limit:	929-930	1.5				
LITTIIL.	935–940 1427–1435	0.1 300	1.5 300	1.5 300		
	Above 2450	300		300		
	 (a) The frequency offset shall be measured according to the procedure described in RSS-Gen andrecorded; (b) Using a resolution bandwidth of 1% of the occupied bandwidth, a reference point at the unwantedemission level specified in Section 5.7 on the emission mask of the lowest and highest channel shallbe selected, and the frequency at these points shall be recorded as fL and fH respectively. The applicant shall ensure frequency stability by showing that fL minus the frequency offset and fH plusthe frequency offset shall be within the 3650-3700 MHz band. 					
Test setup:		Temperature Chamber				
Tost procedure:	Note: Measurement setup	Att.				
Test procedure: 1. Set chamber temperature to 25℃. Use a variab to power the EUT and set the voltage to rated vo				je.		
	2. Set the spectrum analyzer RBW low enough to obtain the					
	frequency resolu	tion and record	led the frequency.			
	· ·		pecify extreme volta	age variation (+/-		
	maximum frequency					
Test Instruments:	Refer to section 5.8 fc	Refer to section 5.8 for details				
Test mode:		Refer to section 5.3 for details, and all channels have been tested, only shows the worst channel data in this report.				
Test results:	Passed	Passed				
Remark:	All three channels of	All three channels of all modulations have been tested, but only the worst				
. Comani.		channel and the worst modulation show in this test item.				



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Measurement Data (the worst channel):

Chain 0:

Reference Frequency: Lowest channel=3655MHz(10MHz for QPSK)					
Temperature (°C)	Power supplied (Vdc)	Frequency error			
		Hz	ppm		
25	42	99	0.027086		
	48	85	0.023256		
	58	74	0.020246		
Reference Frequency: Lowest channel=3660MHz(20MHz for QPSK)					
Temperature (°C)	Power supplied (Vdc)	Frequency error			
		Hz	ppm		
25	42	86	0.023497		
	48	85	0.023224		
	58	59	0.016120		

Chain 1:

Reference Frequency: Lowest channel=3655MHz(10MHz for QPSK)					
Temperature (°C)	Power supplied (Vdc)	Frequency error			
		Hz	ppm		
25	42	102	0.027907		
	48	91	0.024897		
	58	73	0.019973		
Reference Frequency: Lowest channel=3660MHz(20MHz for QPSK)					
Temperature (°C)	Power supplied (Vdc)	Frequency error			
		Hz	ppm		
25	42	90	0.024590		
	48	88	0.024044		
	58	64	0.017486		